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Sommario/riassunto	The stuck-open fault (SOF) is a difficult, hard failure mechanism unique to CMOS technology [1-3]. Its detection requires a specific 2-vector pair that examines each transistor in the logic gate for an open defect in its drain and/or source. This defect defies a guaranteed 100% detection. We will show that this mostly discarded failure mechanism is very relevant to modern ICs. Current leakage in nanoscale technologies influence significantly the behavior of this fault.